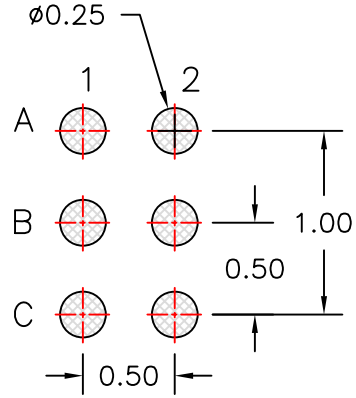
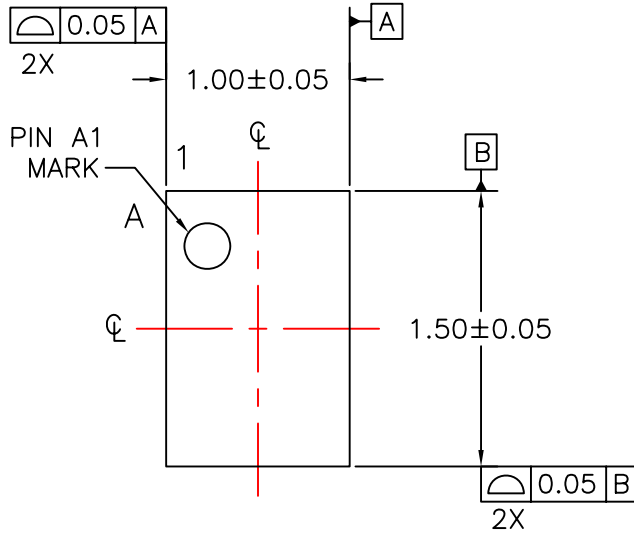
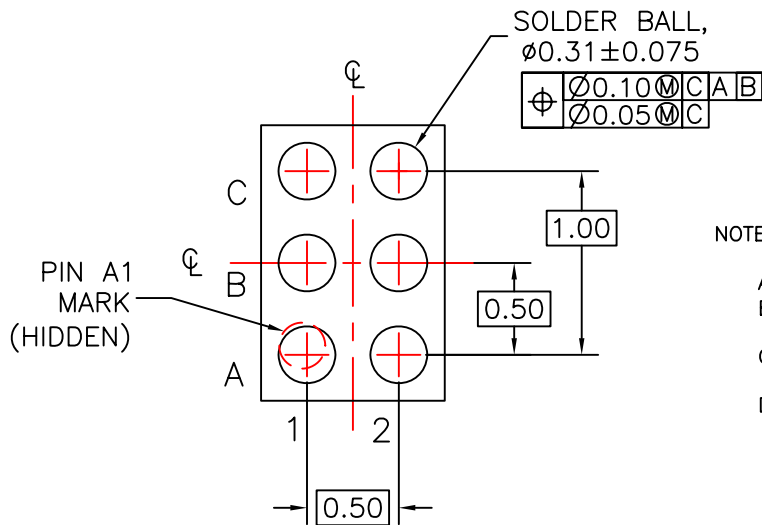
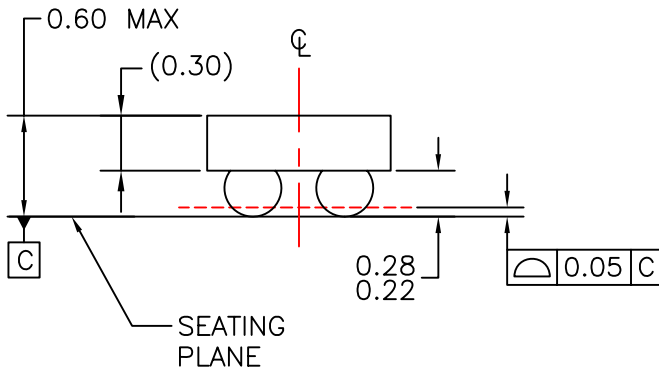


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REVISIONS			
LTR	DESCRIPTION	DATE	NAME/SITE
A	RELEASE TO DOCUMENT CONTROL	9NOV2001	RPM/FSCP
B	PIN 1 MARK FR SQUARE TO CIRCLE; PKG LENGTH&WIDTH TOL FR ± 0.15 TO ± 0.10 ; CHG TOT PKG HEIGHT FR 0.75 MAX TO 0.65 MAX; CHG PKG THICKNES FR 0.50 TO 0.30; CHG BALL HEIGHT FR 0.15 TO 0.22-0.28; CHG BALL COPLANARITY FR 0.075 TO 0.10; CHG BALL DIM FR $\phi 0.18 \pm 0.018$ TO $\phi 0.31 \pm 0.075$; CHG LAND PATTERN DIA DIM FR $\phi 0.16$ TO $\phi 0.25$	1MAR2006	RNM/FSCP
C	CHG LEADER FR GATE PIN MARK TO PIN A1 MARK, REMOVE GATE LEADER ON LAND PATTERN, REMOVED NOTE C, DELETE SINKET FET ON DWG TITLE	18AUG2006	RNM/FSCP
4	CHG PKG WIDTH AND LENGTH TOLERANCE FROM ± 0.10 TO ± 0.05 ; 1.0 ± 0.10 TO 1.0 ± 0.05 AND 1.50 ± 0.10 TO 1.50 ± 0.05 ; TOTAL PACKAGE THICKNESS FROM 0.65 MAX TO 0.6 MAX; CHG COPLANARITY FR 0.10 TO 0.05; ADD NOTE C.	17APR2008	JMM/FSCP



LAND PATTERN RECOMMENDATION



NOTES: UNLESS OTHERWISE SPECIFIED

- A) ALL DIMENSIONS ARE IN MILLIMETERS.
- B) NO JEDEC REGISTRATION REFERENCE AS OF OCTOBER 2005.
- C) DRAWING CONFORMS TO ASME Y14.5M-1994
- D) TERMINAL CONFIGURATION TABLE.

GATE	SOURCE	DRAIN
A1	A2, B1, B2	C1, C2

E) DRAWING FILENAME: MKT-UC006AArev4

APPROVALS	DATE	
DRAWN: J. COMPARATIVO JR. CHECKED: J. V. MANCELITA APPROVED: M. GESTOLE G.S. BAJE	17APR2008	
		SCALE: 1:1 SIZE: NA FORMERLY: N/A
		DRAWING NUMBER: MKT-UC006AA REV: 4 SHEET: 1 OF 1